Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
07977-008004Application No.
09/504,235**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Shunpei Yamazaki, Yasuyuki Arai, and Satoshi
TeramotoFiling Date
February 15, 2000Group Art Unit
2775**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>QX</i>	AA	5,346,850	Sep. 13, 1994	Kaschmitter et al			
	AB						
	AC						
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	AE						
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	AK						

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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

DAVID L LEWIS

Date Considered

3/15/01

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(37 CFR § 1.101)

Applicant
Shunpei Yamazaki, Yasuyuki Arai, and Satoshi Teramoto

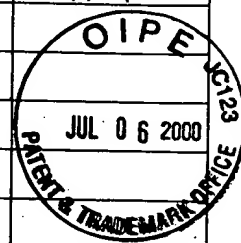
Filing Date
February 15, 2000

Group Art Unit
2775

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Examiner Initial	Desig. ID	Patent Number
<i>[Signature]</i>	AA	5,147,826
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Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
09/15/92	Liu, et al.			



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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number
<i>[Signature]</i>	AL	WO 92/12451
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	AP	

Publication Date	Country or Patent Office	Class	Subclass	Translation	
				Yes	No
07/23/92	PCT			X	

Other Documents (Include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
<i>[Signature]</i>	AS	Gang Liu & H. Fonash, Selective area crystallization of amorphous silicon films by low-temperature rapid thermal annealing, Appl. Phys. Lett. 55, pp. 660-662, 1989
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Document
Gang Liu & H. Fonash, Selective area crystallization of amorphous silicon films by low-temperature rapid thermal annealing, Appl. Phys. Lett. 55, pp. 660-662, 1989

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next examination, applicant.

Date Considered

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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977/008002/US2938D1	Application No. 09/013,960
	Applicant Shunpei Yamazaki, et al.		
	Filing Date January 27, 1998	Group Art Unit 2822	

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<i>[Signature]</i>	AA	4,643,526	2/17/87	Watanabe, et al.			
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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
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	AL							

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Examiner Initial	Desig. ID	Document
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	AR	

Examiner Signature <i>DAVID L LEWIS</i>	Date Considered <i>3/15/01</i>
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